

## N-Channel Enhancement Mode Field Effect Transistor

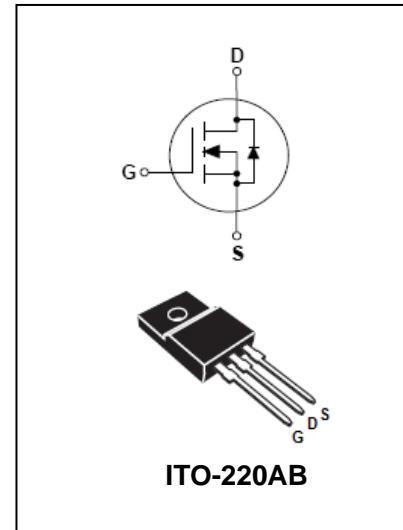
**BL8N40F**

### FEATURES

- RDS(ON) = 1.2Ω@VGS = 10V.
- Ultra Low gate charge (typical 28nC)
- Low reverse transfer capacitance (CRSS = typical 12.0 pF)
- Fast switching capability
- Avalanche energy specified
- Improved dv/dt capability, high ruggedness



Lead-free



### MAXIMUM RATING @ Ta=25°C unless otherwise specified

Symbol	Parameter	Value	Units
V <sub>DS</sub>	Drain-Source voltage	400	V
V <sub>GS</sub>	Gate -Source voltage	±30	V
I <sub>D</sub>	Continuous Drain current T <sub>C</sub> =25°C	8	A
E <sub>AS</sub>	Single Pulse Avalanche Energy(Note2)	320	mJ
E <sub>AR</sub>	Avalanche Energy,Repetitive(Note1)	2.5	mJ
P <sub>D</sub>	Power Dissipation	39	W
	Derate above 25°C	0.312	W/°C
R <sub>θJC</sub>	Junction-to-Case	3.18	°C/W
R <sub>θJA</sub>	Junction-to-Ambient	62.5	°C/W
T <sub>J</sub> , T <sub>stg</sub>	Junction and Storage Temperature	-55 to +150	°C
T <sub>L</sub>	Maximum Temperature for Soldering	+150	°C

Note: 1.Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is implied.

2.Repetitive Rating: Pulse width limited by maximum junction temperature

3.L = 10mH, IAS = 8A, VDD = 50V, RG = 25Ω, Starting TJ = 25°C

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ELECTRICAL CHARACTERISTICS @ Ta=25°C unless otherwise specified

Parameter	Symbol	Test conditions	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	400	-	-	V
Bvdss Temperature Coefficient	△BV <sub>DSS</sub> / △T <sub>J</sub>	I <sub>D</sub> =250mA, Reference to 25°C,	-	0.4	-	V/°C
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250μA	2.0		4.0	V
Drain to Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =400V, V <sub>GS</sub> =0V	-	-	10	μA
Static drain-Source on-resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =4A	-	0.68	0.82	Ω
Gate-body Leakage Forward Reverse	I <sub>GSS</sub>	V <sub>GS</sub> =±30V			± 100	nA
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V V <sub>DS</sub> = 25V f = 1.0MHz (Note 1, 2)	-	-	1600	pF
Output Capacitance	C <sub>oss</sub>		-	-	450	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	-	150	
Turn-on Delay Time	t <sub>d(ON)</sub>	VDD=200V, ID=8A, RG=25Ω (Note 1, 2)	-	-	35	ns
Rise Time	t <sub>r</sub>		-	-	15	
Turn-Off Delay Time	t <sub>d(OFF)</sub>		-	-	90	
Fall Time	t <sub>f</sub>		-	-	35	

Note: 1. Pulse Test: Pulse width ≤ 300μs, Duty cycle ≤ 2%

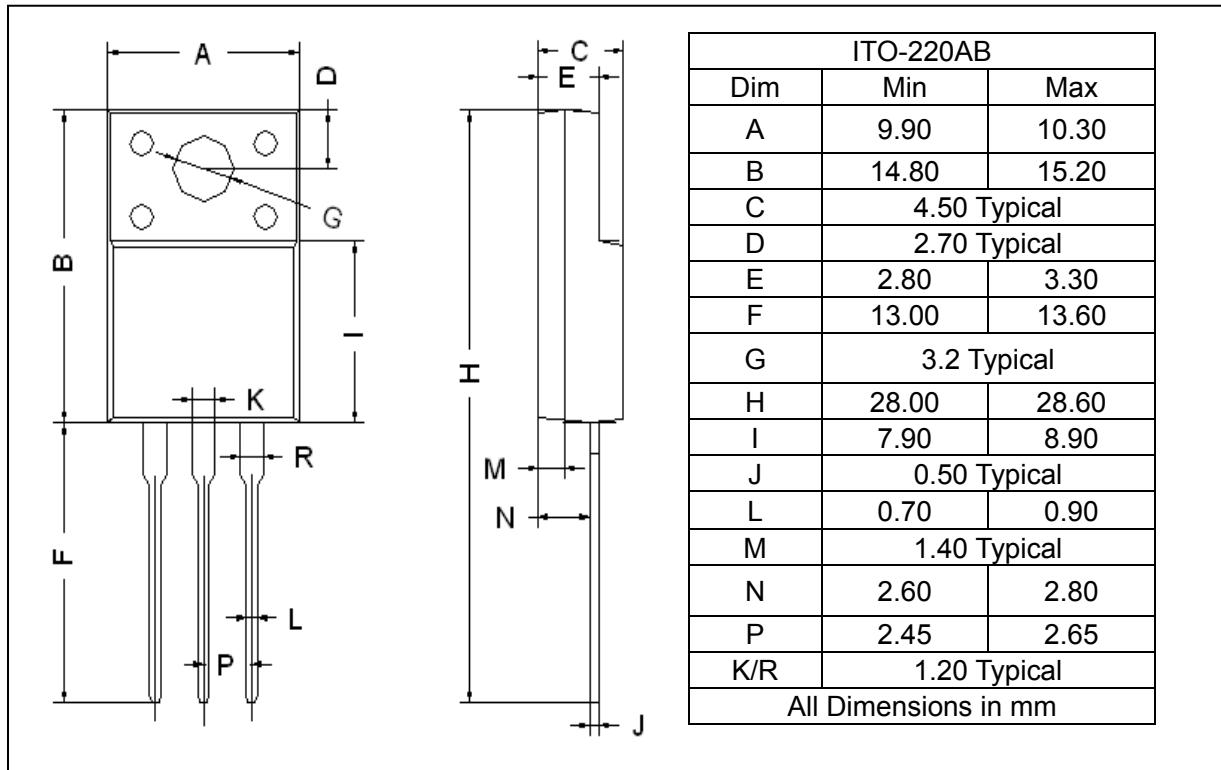
2. Essentially independent of operating temperature

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### PACKAGE OUTLINE

Plastic surface mounted package

ITO-220AB



ITO-220AB		
Dim	Min	Max
A	9.90	10.30
B	14.80	15.20
C	4.50 Typical	
D	2.70 Typical	
E	2.80	3.30
F	13.00	13.60
G	3.2 Typical	
H	28.00	28.60
I	7.90	8.90
J	0.50 Typical	
L	0.70	0.90
M	1.40 Typical	
N	2.60	2.80
P	2.45	2.65
K/R	1.20 Typical	
All Dimensions in mm		